

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination WIMMER ET AL.	
		Examiner Marianne L. Padgett	Art Unit 1762	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,756,765	07-1988	Woodroffe, Jaime A.	134/1
*	B	US-4,803,021	02-1989	Werth et al.	264/400
*	C	US-5,597,621 A	01-1997	Hummel et al.	427/554
*	D	US-4,868,006	09-1989	Yorkgitis et al.	427/555
*	E	US-5,595,791 A	01-1997	Baumgart et al.	427/554
*	F	US-5,968,608 A	10-1999	Xuan et al.	427/555
*	G	US-5,582,878 A	12-1996	Ogawa et al.	427/554
*	H	US-6,022,596 A	02-2000	Baum et al.	430/315
*	I	US-6,120,131 A	09-2000	Murthy et al.	347/47
*	J	US-5,172,473 A	12-1992	Burns et al.	29/885
*	K	US-2005/0242059 A1	11-2005	Brennen et al.	216/041
*	L	US-6,919,162 B1	07-2005	Brennen et al.	430/272.1
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Krajnovich Et Al., "Formation of 'Intrinsic' Surface Defects During 248 Nm Photoablation of Polyimide", J. Applied Physics, volume 73, #6, March 15, 1993, pages 3001-3008.
	V	Douglas Krajnovich, "Year-Threshold Photoablation Characteristics of Polyimide and Poly (Ethylene Terephthalate)", J. Applied Physics, Volume 82, #1, July 1, 1997, pages 427-435
	W	You
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.